Docket No.: 50090-247

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	
Osamu HASHIMOTO, et al.	:	
Serial No.: 09/730,750	:	Group Art Unit: 2856
Filed: December 07, 2000	:	Examiner: Jimmy Nguyen

For: APPARATUS AND METHOD OF INSPECTING SEMICONDUCTOR INTEGRATED CIRCUIT

AMENDMENT

Commissioner for Patents
Washington, DC 20231

Sir:

The following amendments and remarks are respectfully submitted in response to the Office Action dated January 30, 2002.

IN THE SPECIFICATION:

Please replace the paragraph beginning at page 11, line 17, with the following rewritten paragraph:

--Further, in the structure of the burn-in board 12 according to the present embodiment, a space is ensured between the burn-in board 12 and the exchange board 22 by means of the spacers 20. Providing a bypass capacitor on a power line pattern or a GND pattern is effective for eliminating noise which would otherwise be superimposed on the power line pattern or the GND pattern. According to the present embodiment, a bypass capacitor can be placed in the space defined between the burn-in board 12 and the exchange board 22. In this respect, the structure of the burn-in board 12 according to the present